

# Causal Inference with Treatment Measurement Error

## A Non-parametric Instrumental Variable Approach

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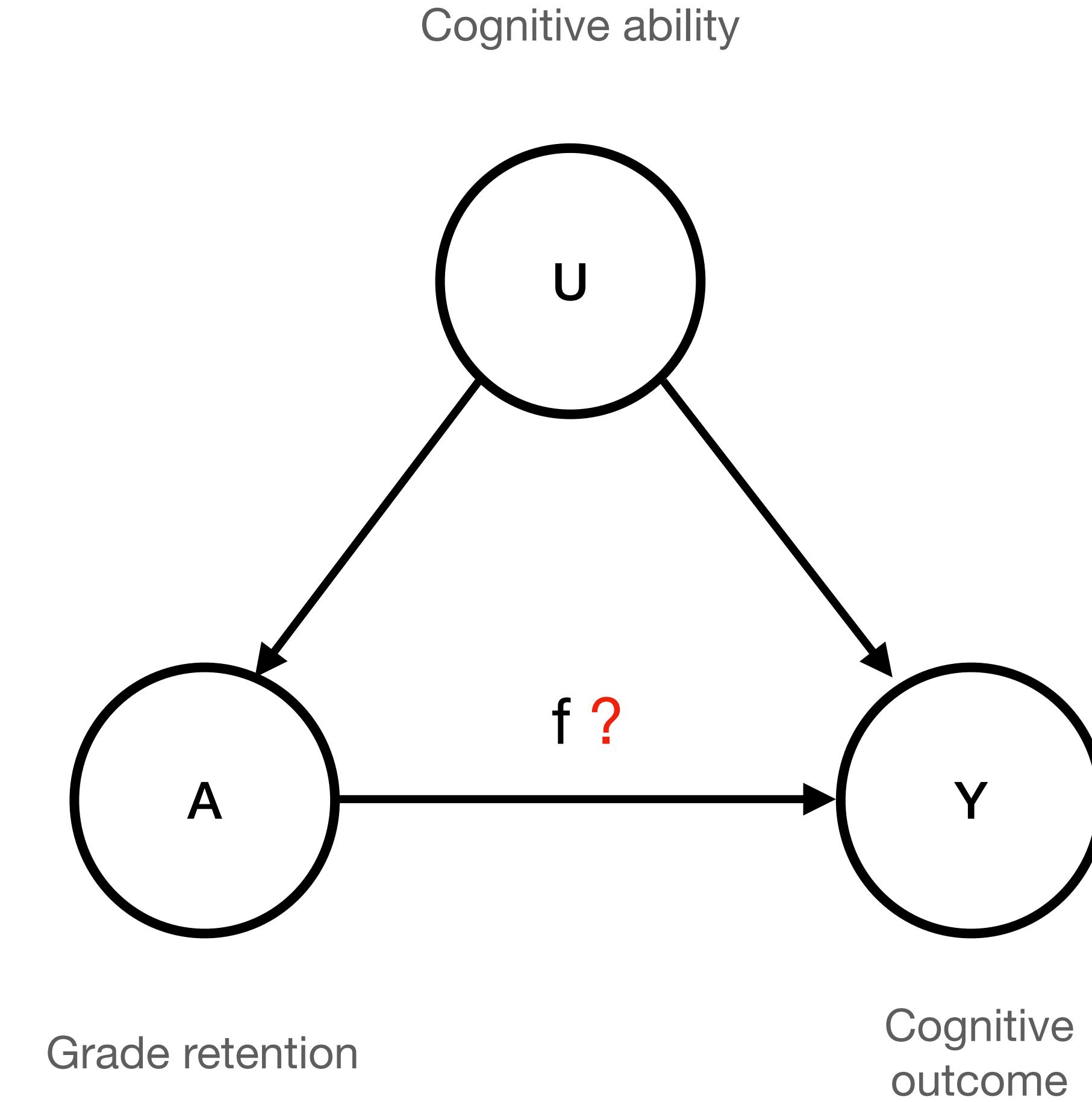


**Oxford talk 10.2022**

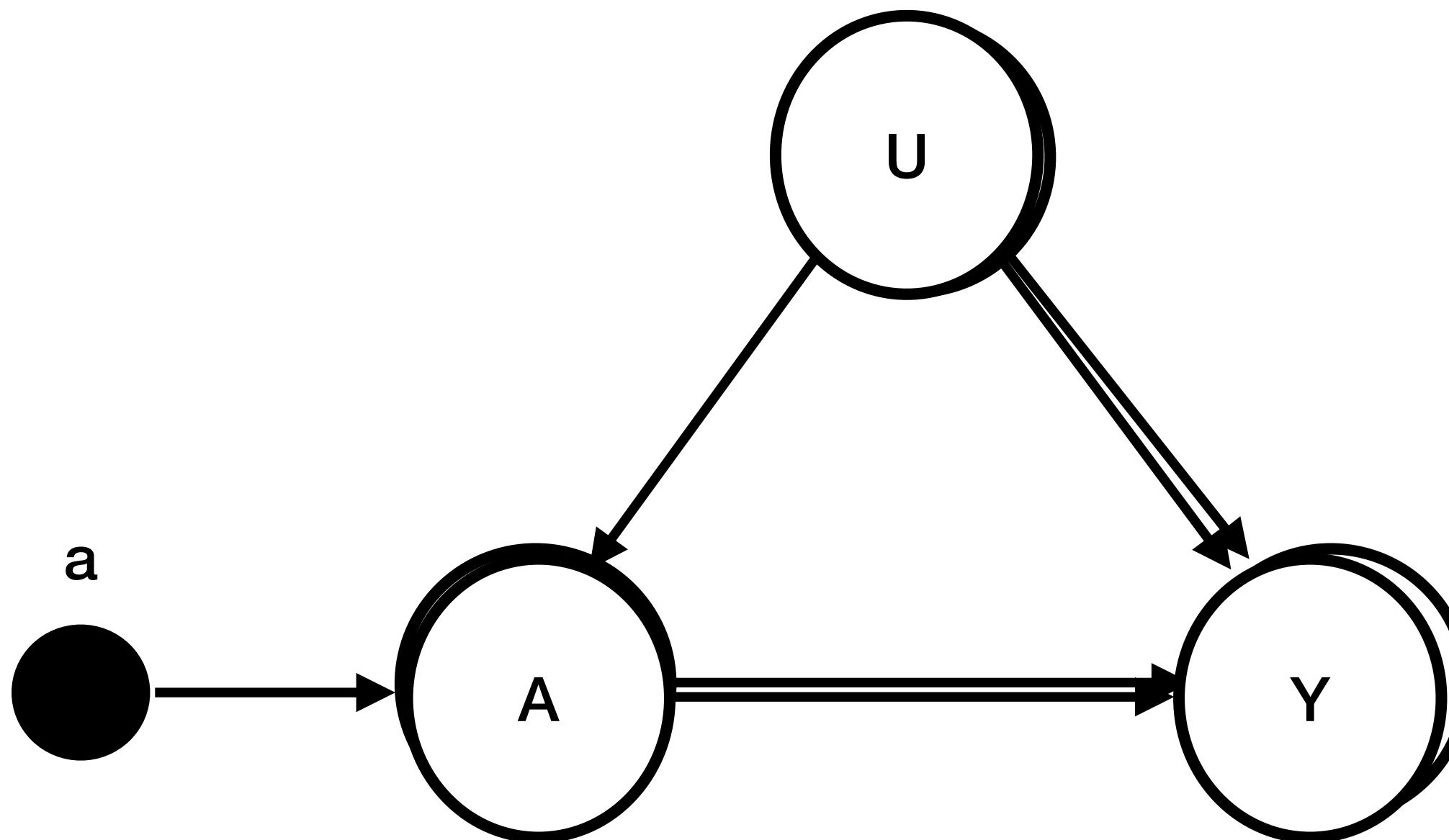
# Causal inference in the real world



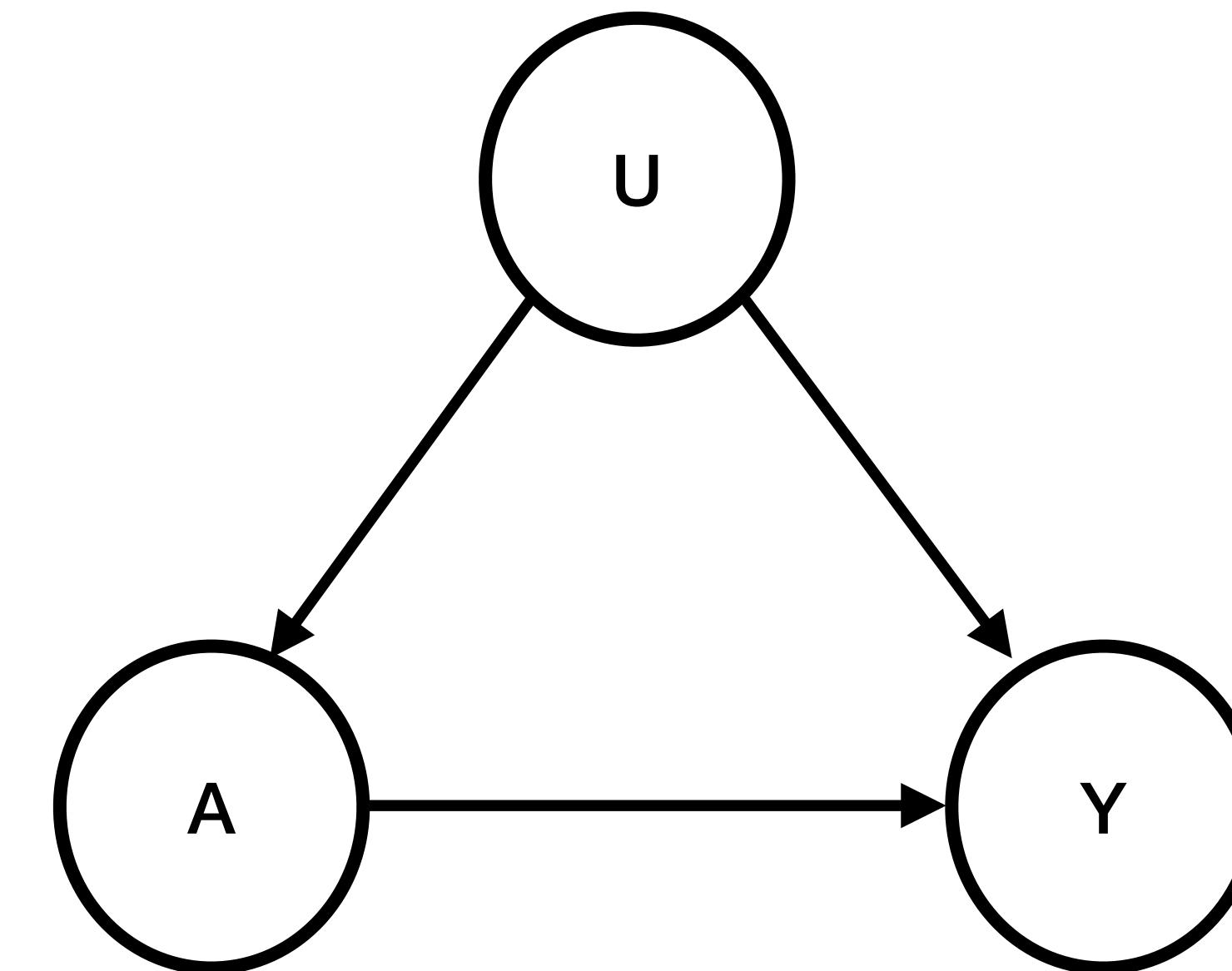
Image source: Google image



# Target quantity from observational data

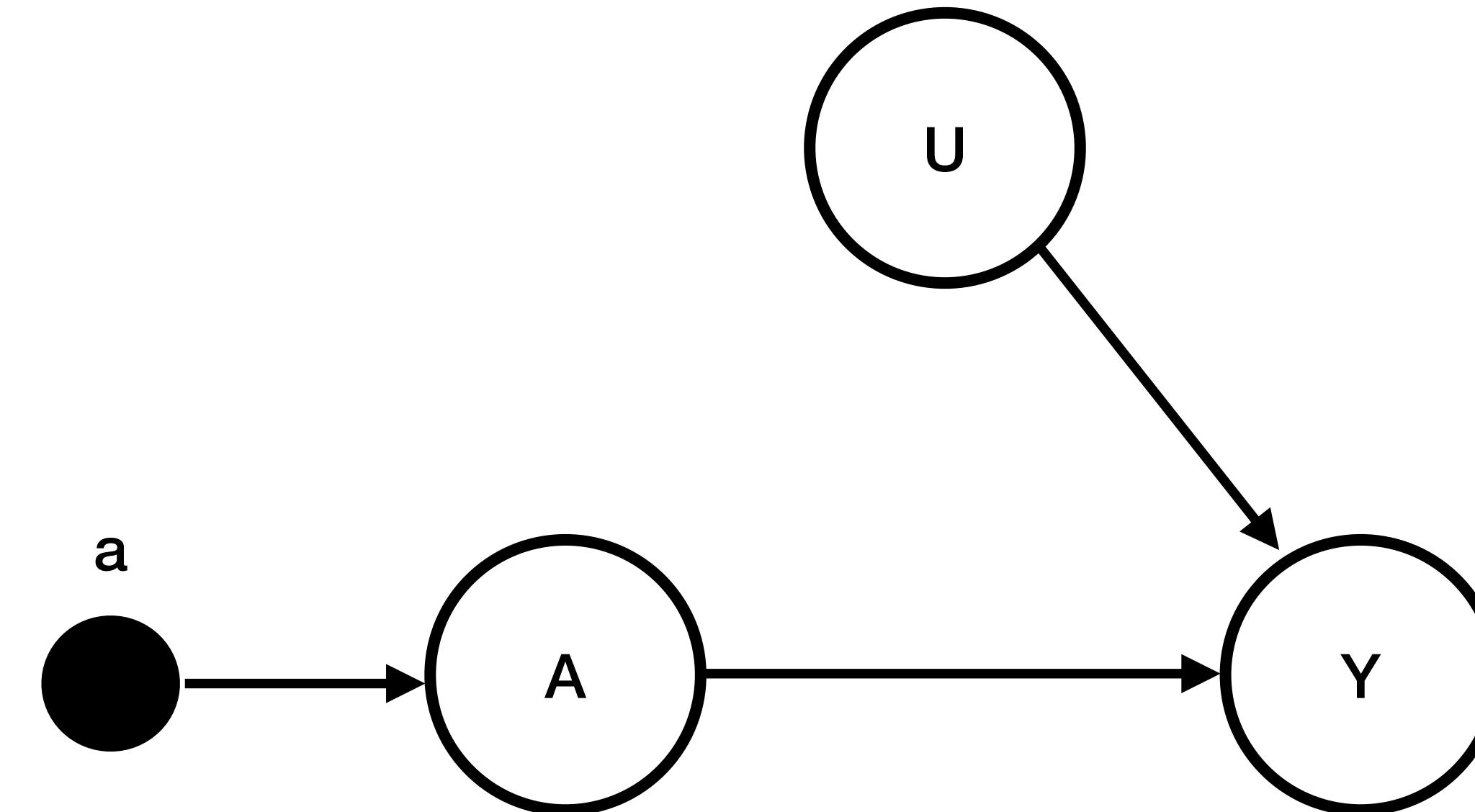
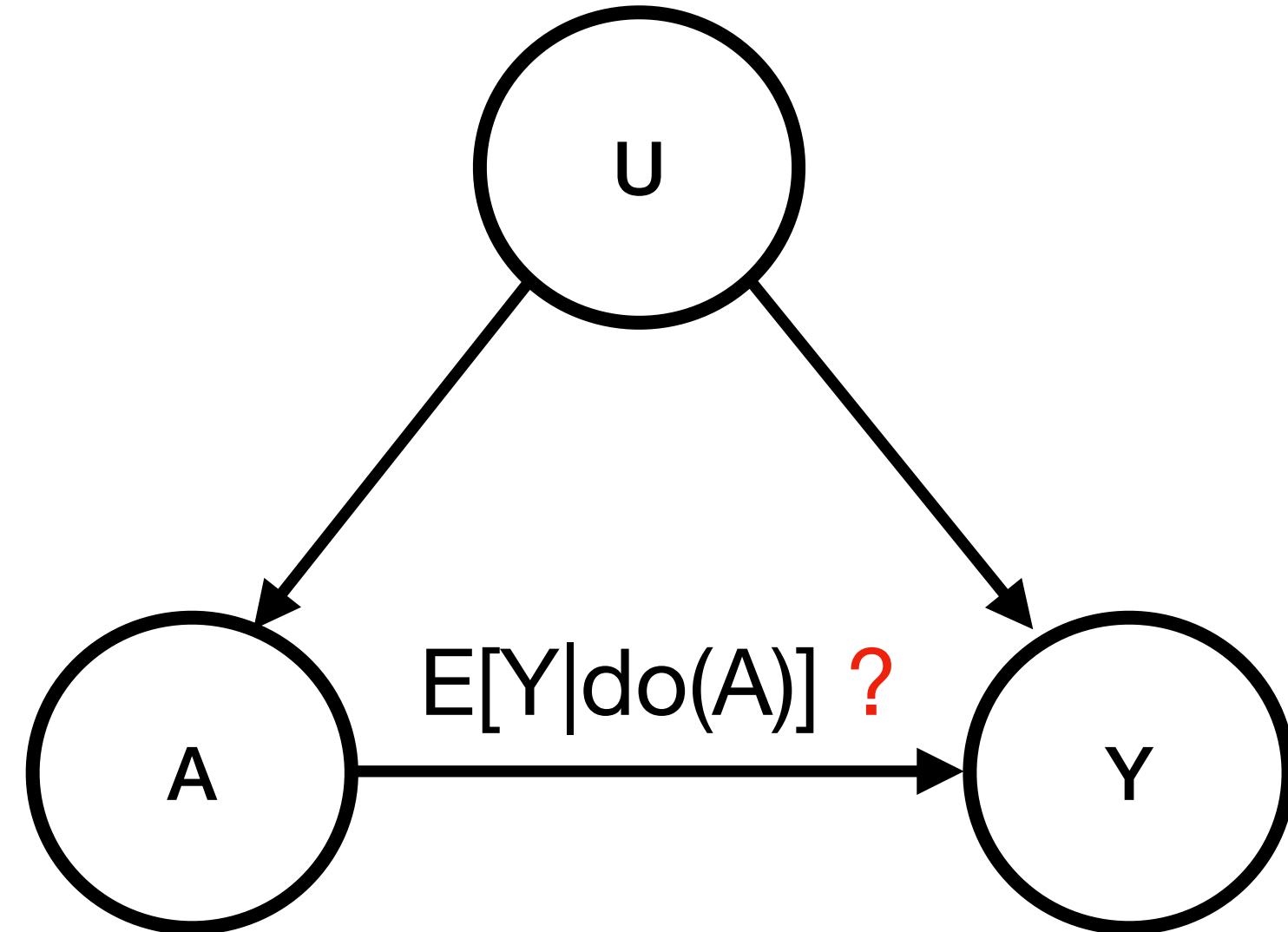


Observed data



Observed data

# Recap: Observed confounders

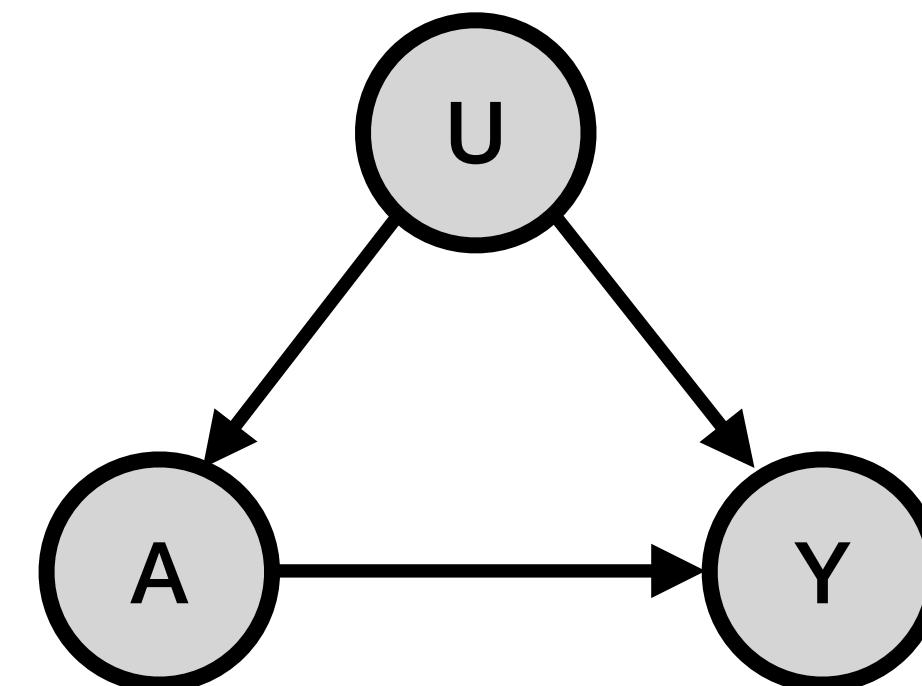
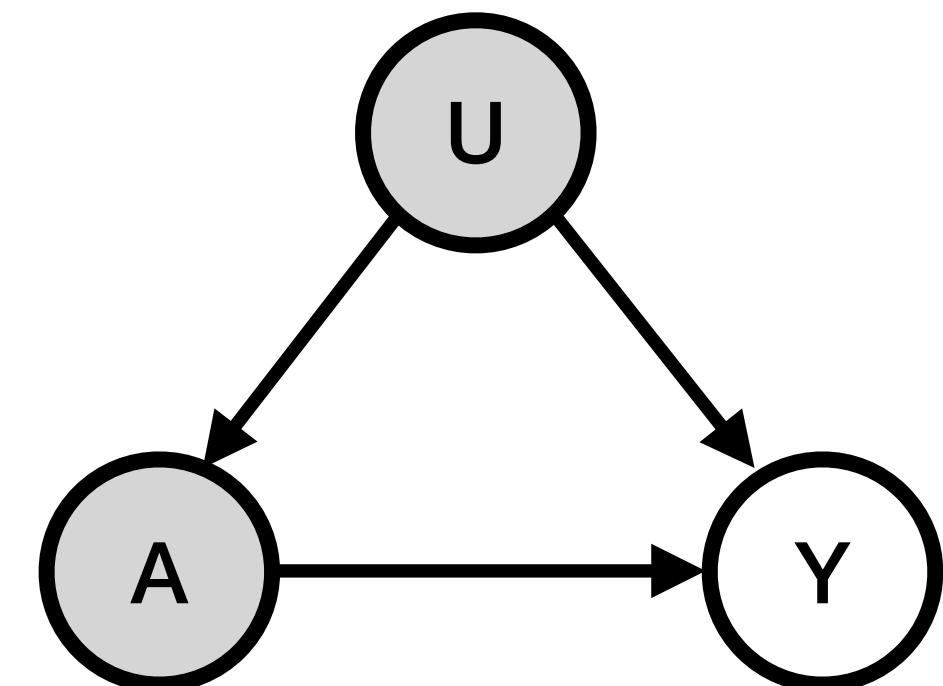
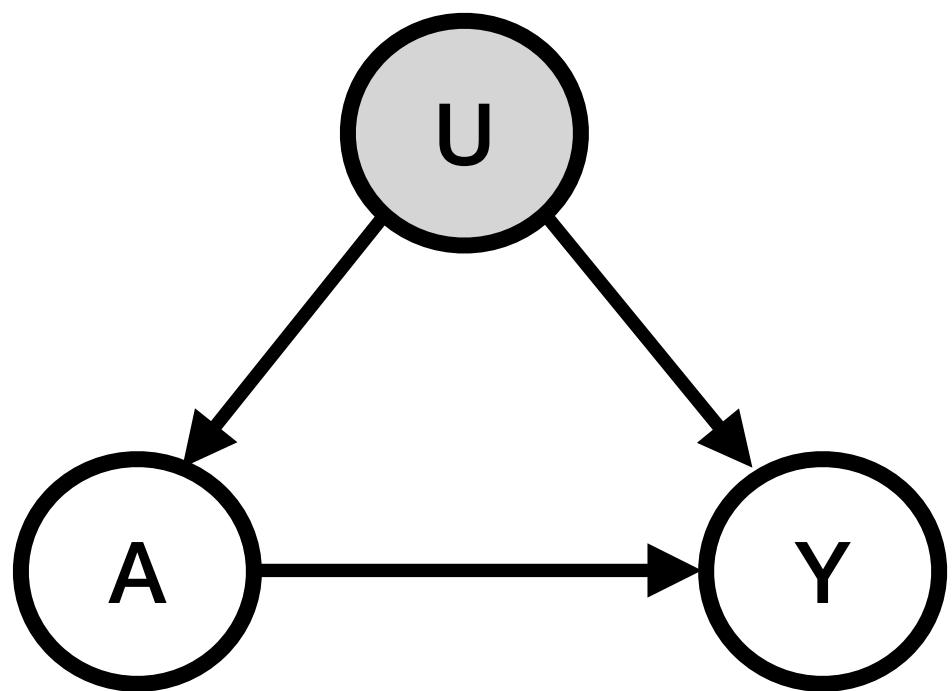


**Backdoor adjustment:**  $\mathbb{E}[Y | do(a)] = \sum_{i=1}^n \mathbb{E}[Y | A = a, U = i] \mathbb{P}(U = i)$

# What are the obstacles?

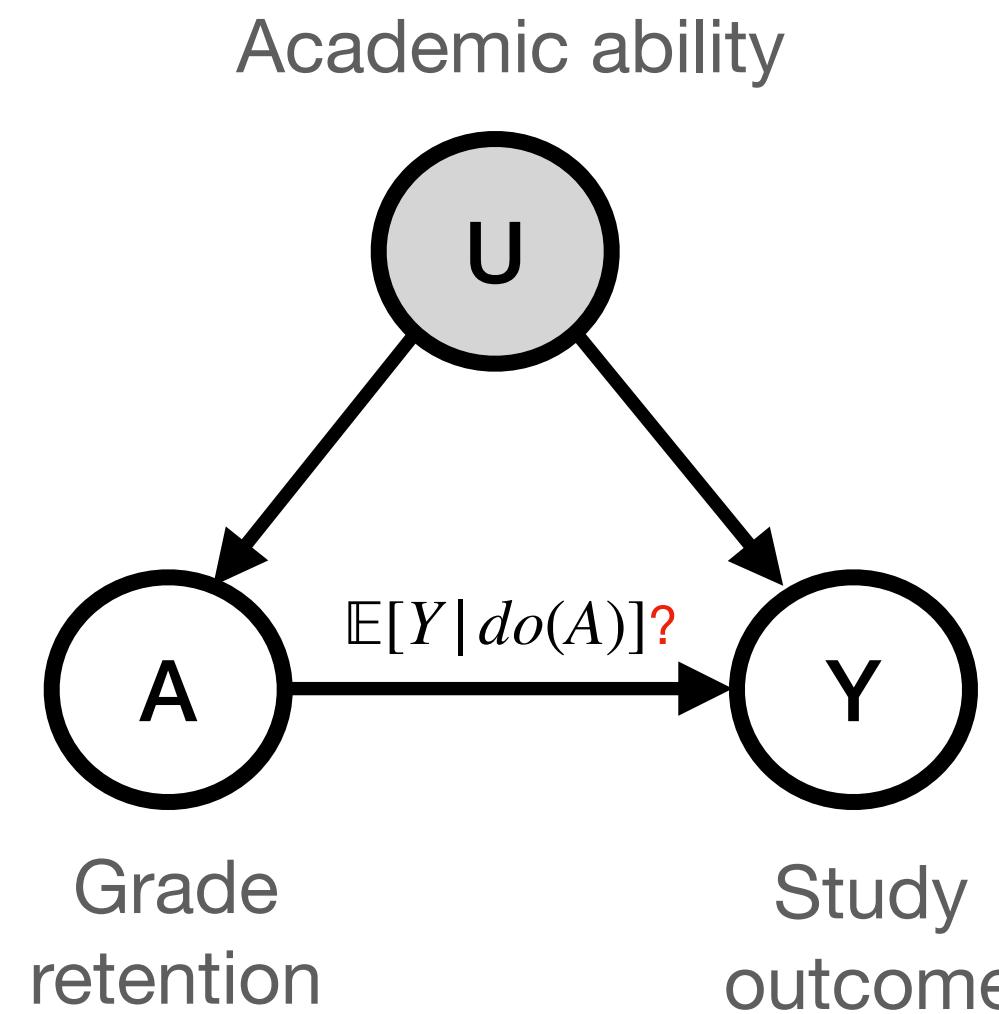
- Disentanglement issues from (observed) U.
  - e.g. U might lead to imbalanced datasets.
- Non-identifiability from latent variables.

<— More on this next

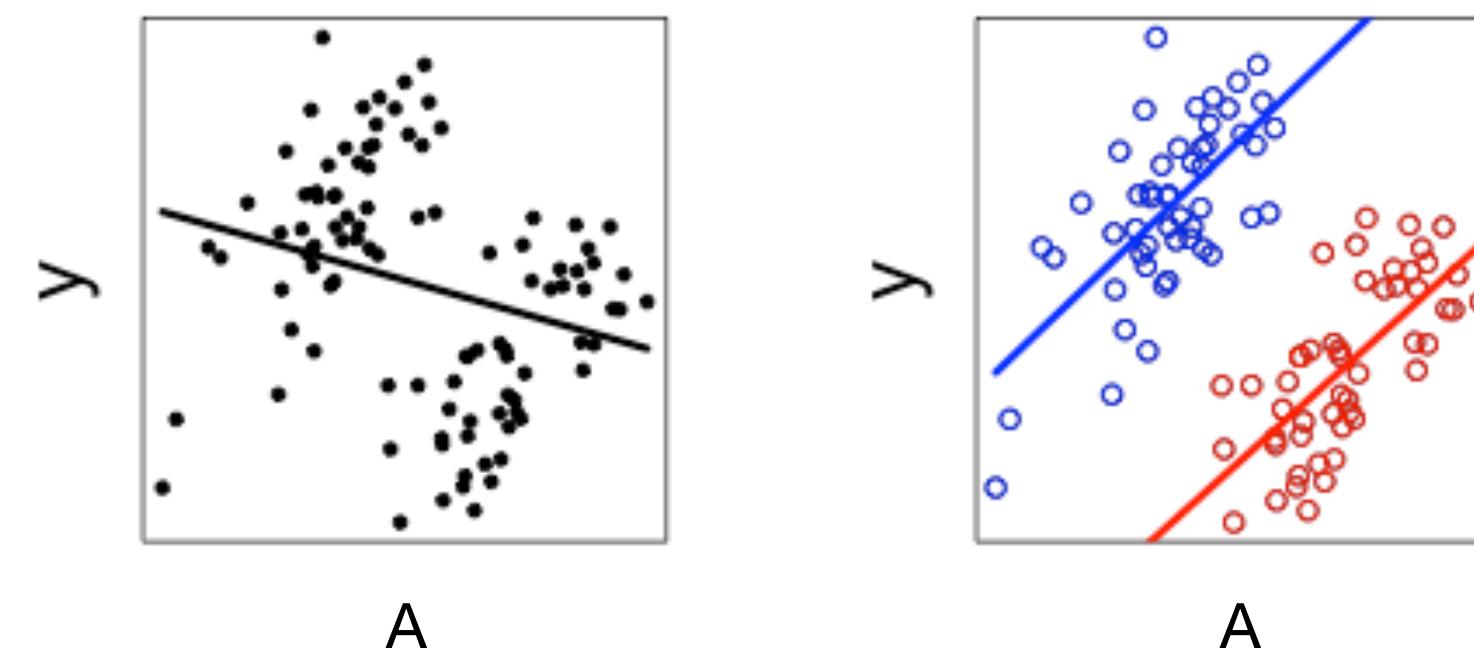


# Why relax observability assumptions?

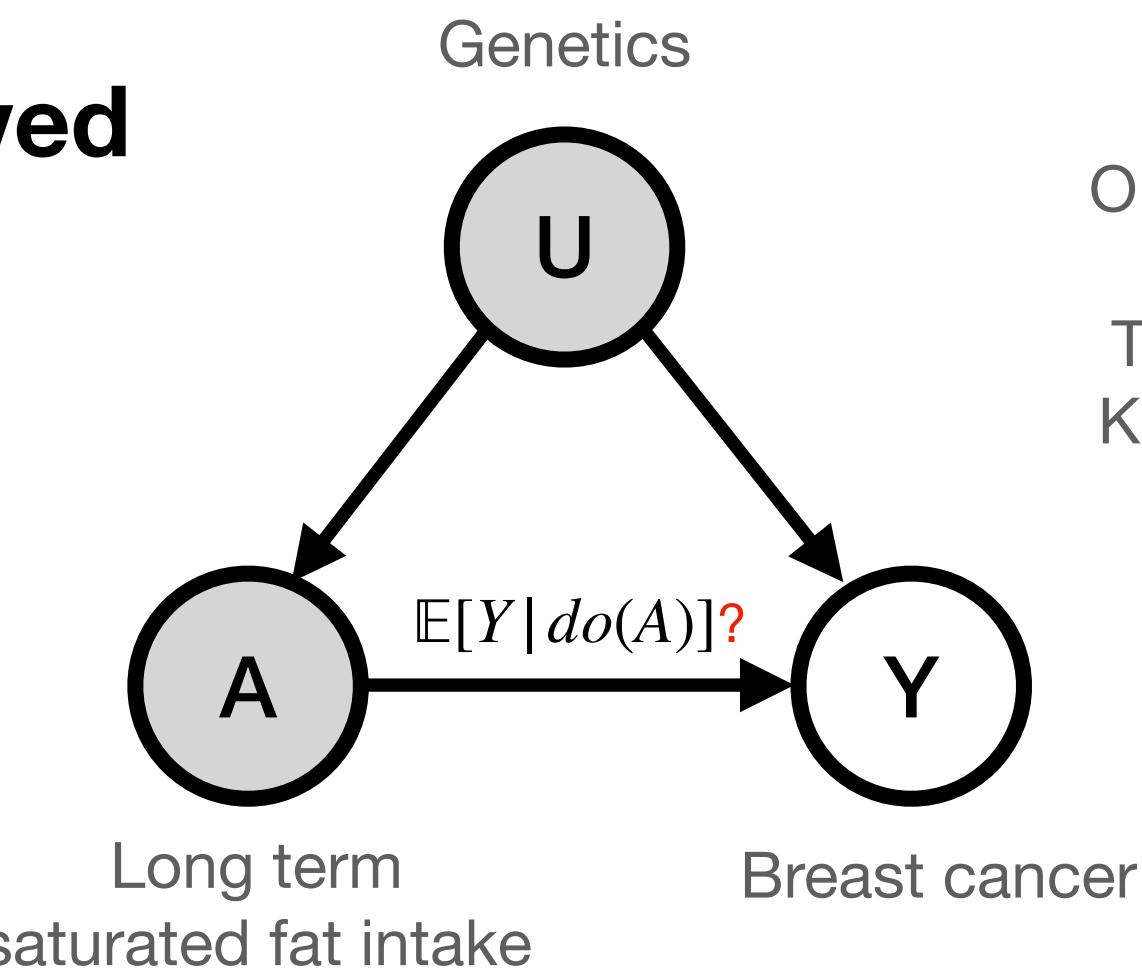
## Unobserved confounders:



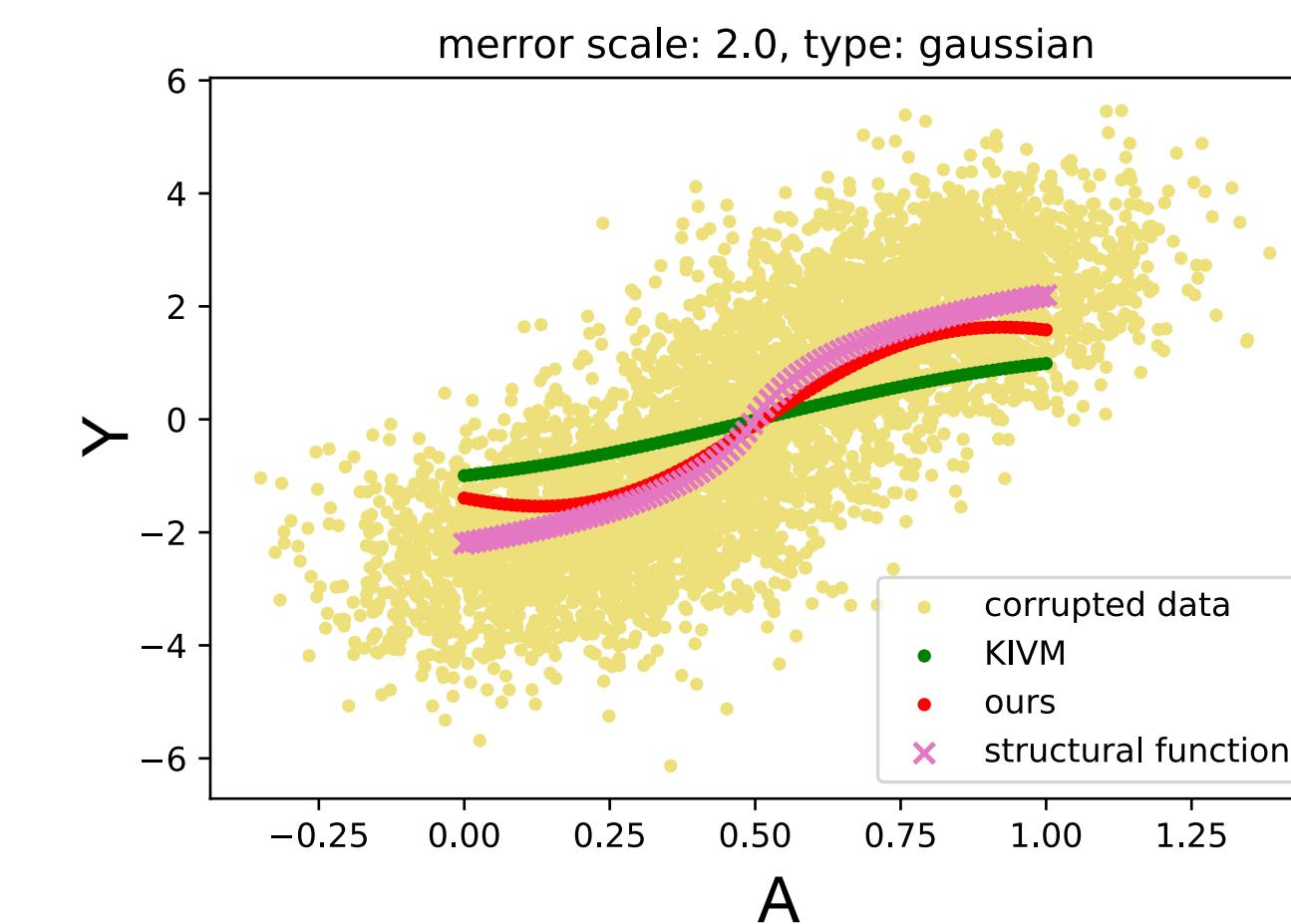
## Simpson's paradox:



## Action observed with error:

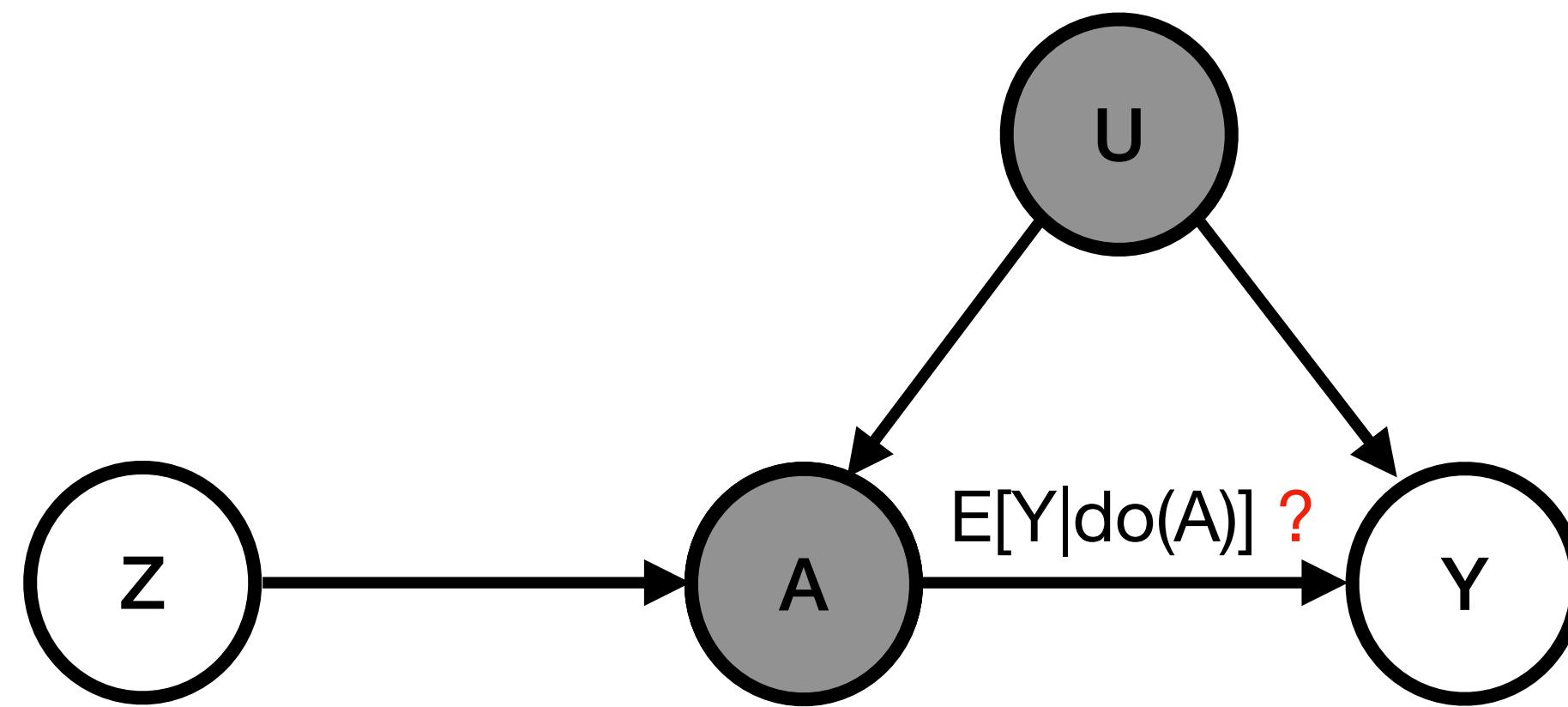


## Mask interesting relationships:



OPEN study:  
Subar,  
Thompson,  
Kipnis, et al.  
2001

# Recap: Identification with instrumental variables



**Identification:**

$$Y = f(A) + \epsilon \quad \mathbb{E}[\epsilon | Z] = 0$$

$$f(A) = \mathbb{E}[Y | do(A)]$$

$$\mathbb{E}[Y | Z] = \int_{\mathcal{A}} f(a)p(a | Z)da$$

**Linear case:**

$$Y = \beta A + \epsilon_Y \quad \epsilon_Y \perp Z$$

$$A = \gamma Z + \epsilon_A \quad \epsilon_A \perp Z$$

$$\Rightarrow Y = \beta\gamma Z + \beta\epsilon_A + \epsilon_Y$$

???

But if  $f(a) = \theta^T \phi(a)$ , then simplifies to

$$\mathbb{E}[Y | Z] = \theta^T \mathbb{E}[\phi(A) | Z]$$

To induce well-posedness:

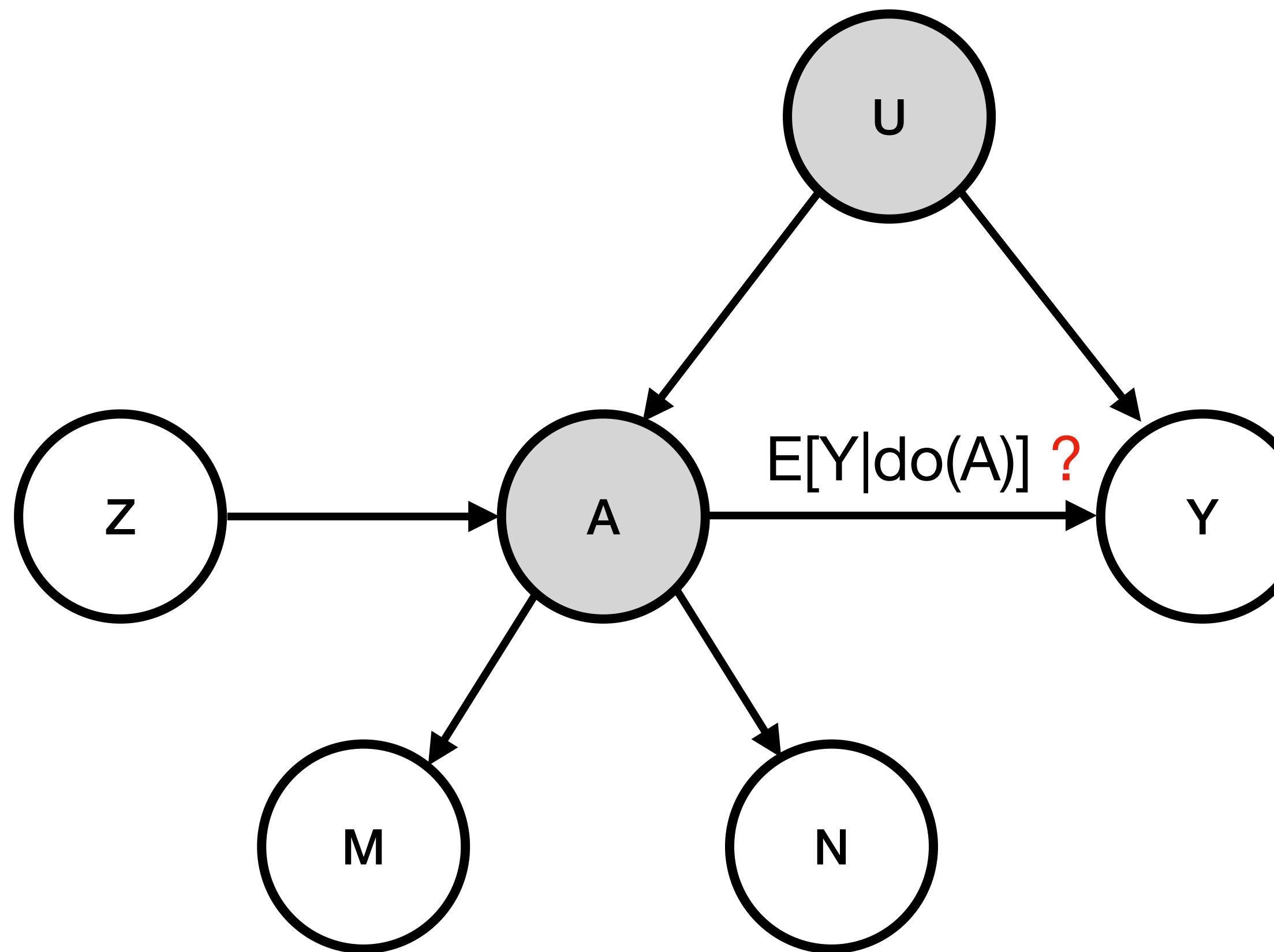
- Assume  $f$  in RKHS.
- Tikhonov regularisation.

**False IV: using same 'IV' for several different actions.**

**(Strong) Assumptions:**

- Additive error model
- $(Z! \perp A)_G$
- $(Z \perp Y)_{G_{\bar{A}}}$

# Measurement error on action variables



# Measurement error on action variables - overview

## Measurement error assumptions

Additive noise on measurements:

$$M = A + \Delta M$$

$$N = A + \Delta N$$

Independence/uncorrelatedness:

$$\mathbb{E}[\Delta M | A, \Delta N] = 0$$

$$\Delta N \perp A$$

## Instrumental identification assumptions

Additive noise on nonlinear response:

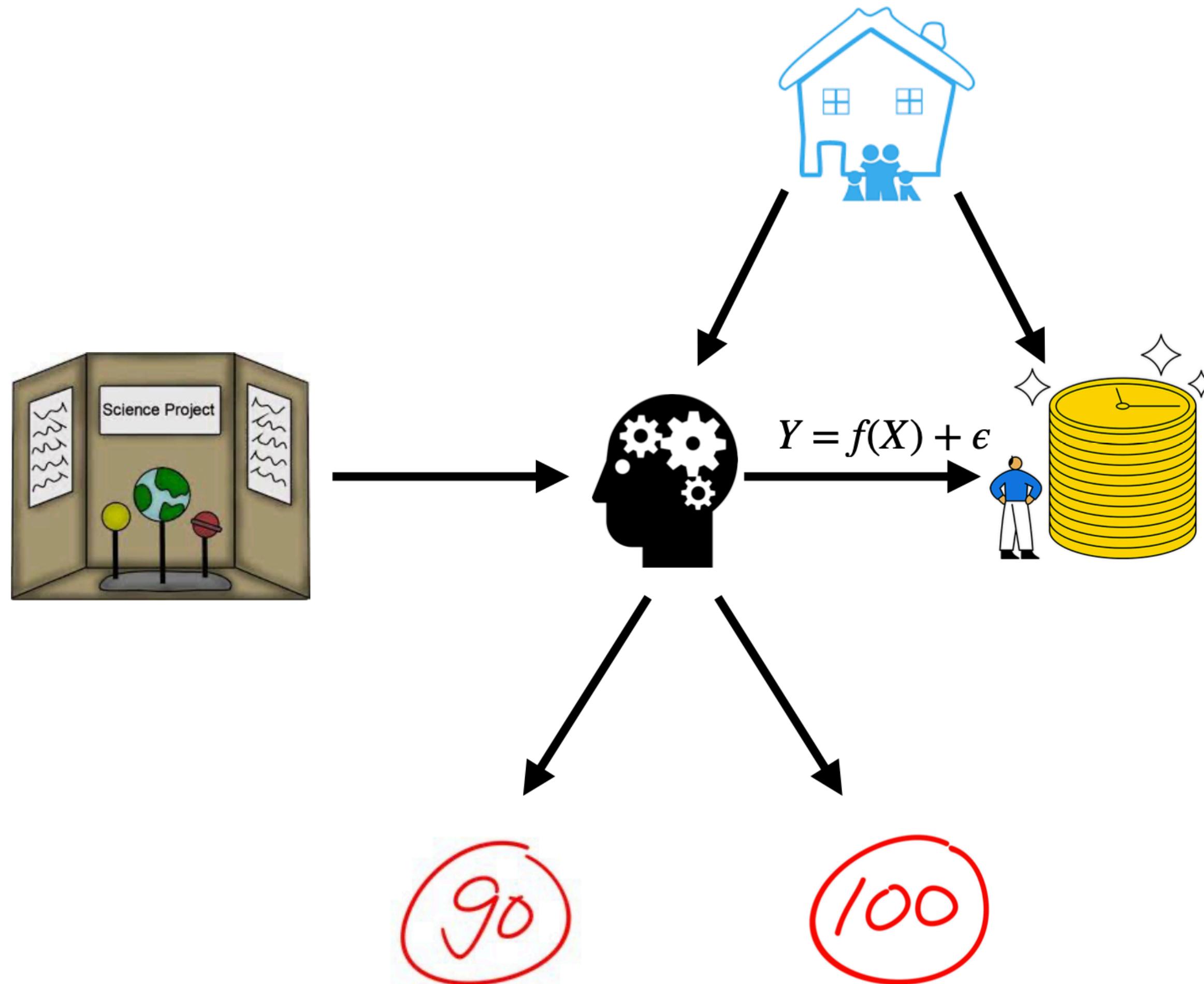
$$Y = f(A) + \epsilon \quad \mathbb{E}[\epsilon | Z]$$

IV structural assumptions:

$$(Z! \perp A)_G$$

$$(Z \perp Y)_{G_{\bar{A}}}$$

# Application scenario



# Measurement error on action variables - overview

Additive noise:

$$M = A + \Delta M$$

$$N = A + \Delta N$$

Independence/uncorrelatedness:

$$\mathbb{E}[\Delta M | A, \Delta N] = 0$$

$$\Delta N \perp A$$

Kotlarski's:

$$\frac{\psi_{A|z}(\alpha)}{\mathbb{E}[e^{iaA} | z]} = \exp\left(\int_0^\alpha i \frac{\mathbb{E}[Me^{i\nu N} | z]}{\mathbb{E}[e^{i\nu N} | z]} d\nu\right) \quad (1)$$

**Parametric assumption:**

- Use  $\psi_{A|Z}$  to get expectations of basis functions by:
- Convolve FT of basis function and characteristic function.

Can we do better? **Yes!**

# From $\hat{\psi}_{A|Z}^n(\alpha)$ to $\hat{\mu}_{A|Z}^n(y)$

$$\frac{\psi_{A|Z}(\alpha)}{\mathbb{E}_{\mathcal{P}_{A|Z}}[e^{i\alpha X}](\alpha)} = \exp\left(\int_0^\alpha i \frac{\mathbb{E}[Me^{i\nu N}|z]}{\mathbb{E}[e^{i\nu N}|z]} d\nu\right) \quad (1)$$

Have  $\hat{\mu}_{A|Z}^n(y) = \sum_{j=1}^n \hat{\gamma}_j^n(z) k(a_j, y)$ .

Let  $\hat{\psi}_{A|Z}^n(\alpha) := \sum_{j=1}^n \hat{\gamma}_j^n(z) e^{i\alpha a_j}$ .

Where  $\hat{\gamma}_j^n(z) = (K_{ZZ} + n\hat{\lambda}^n I)^{-1} K_{Zz}$ .

**Theorem 1.** With translation-invariant, characteristic kernel:

$\hat{\mu}_{A|Z}^n \xrightarrow{n} \mu_{A|Z}$  iff  $\hat{\psi}_{A|Z}^n \xrightarrow{n} \psi_{A|Z}$  in IFT of kernel.

**Assume**  $f \in \mathcal{H}_A$ :

$$\mathbb{E}[Y|Z] = \mathbb{E}[f(A)|Z] = \langle f, \mu_{A|Z} \rangle_{\mathcal{H}_A}$$

**How to get  $\mu_{A|Z}$ ?**

Approximate  $\hat{\mu}_{A|Z}^n$  via  $\hat{\psi}_{A|Z}^n$  (eq.1):

Both only depend on  $\hat{\gamma}_j^n(Z)$  and  $\{a_j\}_{j=1}^n$ !

# Measurement Error KIV

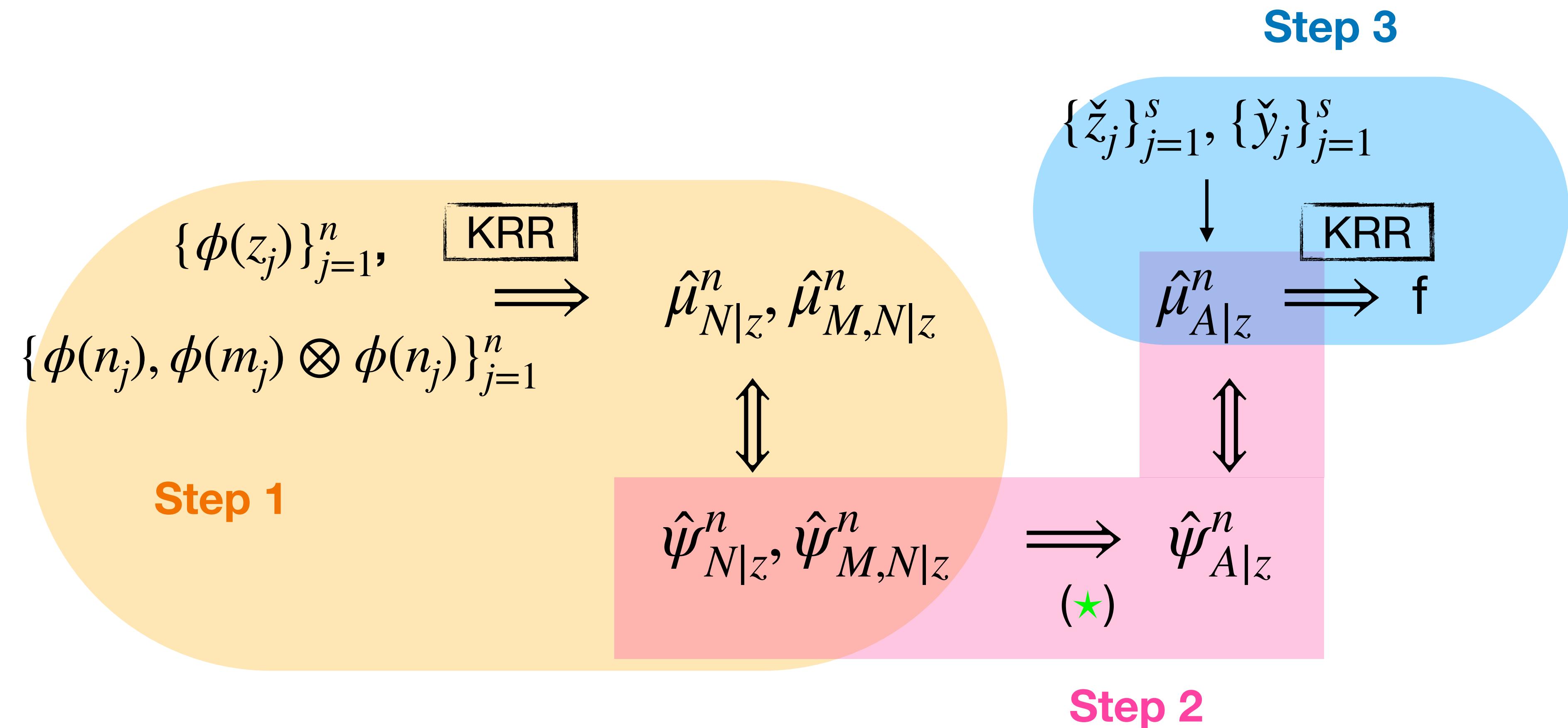
To obtain  $\hat{\psi}_{A|z}^n$ :

$$\frac{\psi_{A|z}(\alpha)}{\mathbb{E}_{\mathcal{P}_{A|z}}[e^{i\alpha X}](\alpha)} = \exp \left( \int_0^\alpha i \frac{\frac{\partial}{\partial v} \psi_{M,N|z}(v, \nu) \Big|_{v=0}}{\underbrace{\mathbb{E}[Me^{i\nu N}|z]}_{\psi_{N|z}(\nu)}} d\nu \right) \quad (1)$$

1. Differentiate wrt  $\alpha$  to remove integral.
2. Replace with sample estimates.

$$\frac{\frac{d}{d\alpha} \hat{\psi}_{A|z}^n(\alpha)}{\hat{\psi}_{A|z}^n(\alpha)} = \frac{\frac{\partial}{\partial v} \hat{\psi}_{M,N|z}^n(v, \alpha) \Big|_{v=0}}{\hat{\psi}_{N|z}^n(\alpha)} \quad (2)$$

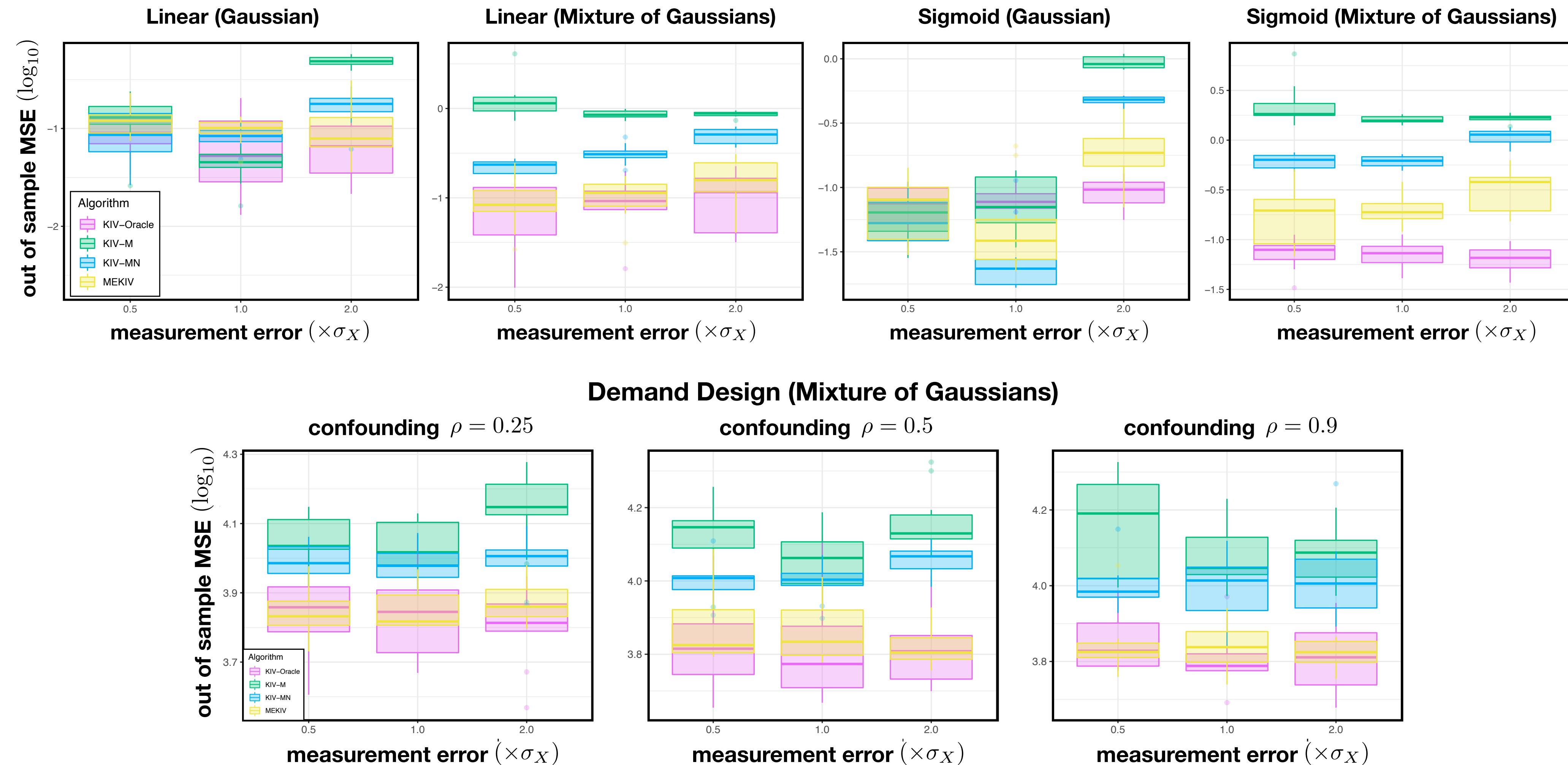
# Measurement Error KIV



# Advantages of MEKIV

- Free of distributional assumptions.
- Only modelling the conditional mean embedding, and not the full distribution.
- No need to train large number of hyperparameters.

# MEKIV results



# Future directions

- Relax the additive error assumption.
- Extend to sequential settings.

Thanks for listening! :)